

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. A-413		SERIAL NO. PCT/JP01/01446	
				T shikazu SEGAWA et al FILING Oct. 25, 2001 (27 Feb. 2001)		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SP		5,327,515	10-1994	Anderson et al			RECEIVED JUN 05 2002
SP		5,981,962	11-1999	Groves et al			TC 1700
<i>(Handwritten diagonal line through the remaining rows of the U.S. Patent Documents table)</i>							
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
SP		936505 ✓	08-1999	EP			
SP		940695 ✓	09-1999	EP			
SP		602829 ✓	06-1994	EP			
SP		9-80738 ✓	03-1997	JP			
SP		7-219243 ✓	08-1995	JP			RECEIVED JUL 14 2003 TC 2800 MAIL ROOM
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
SP			D.M. Tennant et al, Characterization of near-field holography grating masks for optoelectronics fabricated by electron beam lithography, JOURNAL OF VACUUM SCIENCE & TECHNOLOGY B, November/December 1992, Vol. 10, No. 6, pp. 2530-2535				
EXAMINER <i>Suraj Patel</i>				DATE CONSIDERED 6/23/04			

***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
SP	3-188617	08-1991	JP				✓
GP	58-222523	12-1983	JP				✓
GP	59-143324	08-1984	JP				✓
SP	6-36994	02-1994	JP				✓
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
EXAMINER <i>Suny Park</i>				DATE CONSIDERED <i>6/23/04</i>			
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